REMARKS

Claims 1 and 3-29 are pending in this application. Claim 2 is cancelled.

Applicants acknowledge and thank the Examiner for indicating that claims 15 and 27 contain allowable subject matter.

DRAWINGS

Applicants submit replacement drawings for FIGS. 2B and 3. FIG 2B has been amended to designate a first "temperature control" as S12c, a second "temperature control" as S12d, and a third "temperature control" as S12e. FIG. 3 has been labeled as "Prior Art."

CLAIM REJECTION UNDER 35 U.S.C. §103

Claims 1, 3-14, 16-26 and 28-29 are rejected under 35 U.S.C. §103(a) as being unpatentable over Applicants disclosed prior art (APA) in view of Grosch et al. (USP 6,122,760) and Eide (USP 6,014,316). This rejection is also respectfully traversed.

The Examiner alleges that:

> "APA discloses all the elements as mentioned above expect for the burn-in test program is adapted to test each of the semiconductor devices. However, APA discloses testing each of multi-chip package of multiple kinds of semiconductor devices, which requires additional burn-in board and three programs, one for each type of memory (fig. 3). It would have been obvious to a person having an ordinary skill in the art at the time the invention was made to test multi-chip package of multiple kinds of semiconductor devices, i.e., plurality of NAND FLASH Memory or plurality of SRAM or plurality of DRAM using test program of step S10 or S21 respectively[.]" (Emphasis added).

Applicants respectfully submit, based upon the quoted passage above, the Examiner may not have fully appreciated the scope of Applicants claim, for example, independent claim 1 vis-à-vis APA. APA discloses that multi-chip package of multiple kinds of

semiconductor devices, e.g., plurality of NAND FLASH Memory or plurality of SRAM or plurality of DRAM, are each tested by **separate burn-in test programs** in burn-in test equipment. See paragraphs [0008-0013]. In other words, a first test program is uploaded, and then a first memory is tested; a second test program is uploaded, and then a second memory is tested; and a third test program is uploaded, and then a third memory is tested. APA discloses that each memory device must be tested separately with different burn-in test programs. APA does not discloses an integrated burn-in program as alleged by the Examiner.

Claim 1 recites that a method of testing multi-chip package of multiple kinds of semiconductor devices **using an integrated burn-in test program.** The Examiner alleges that APA discloses an integrated burn-in test program. However, as discussed above, APA does not disclose an integrated test program. In addition, the Examiner does not allege nor does either one of the references, Grosch et al and Eide, cure the deficiency of APA.

Applicants submit that the Examiner has failed to make a proper *prima facie* case of obviousness. Accordingly, claims 3-13, and 28, which depend on claim 1, are also patentable for the same reasons given above with respect to the patentability of claim 1.

For the reasons given above with respect to the patentability of claim 1, independent claims 14 and 21 are also patentable, as well their respective dependent claims, because both claims 14 and 21 recite "an integrated burn-in test program."

For at least the reasons given above, Applicants submit that claims 1 and 3-29 are patentable over the Examiner's cited references.

CONCLUSION

In view of the above remarks, reconsideration of the rejections and allowance of claims 1 and 3-29 are respectfully requested.

Should there be any outstanding matters that need to be resolved in the present application, the Examiner is respectfully requested to contact John A. Castellano at the telephone number of the undersigned below. If the Examiner believes that a personal communication will expedite prosecution of this application, the Examiner is invited to telephone the undersigned at (703) 668-8000.

If necessary, the Commissioner is hereby authorized in this, concurrent, and future replies to charge payment or credit any overpayment to Deposit Account No. 08-0750 for any additional fees required under 37 C.F.R. §§ 1.16 or 1.17; particularly, extension of time fees.

Respectfully submitted,

HARNESS, DICKEY & PIERCE, PLC

By _____
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